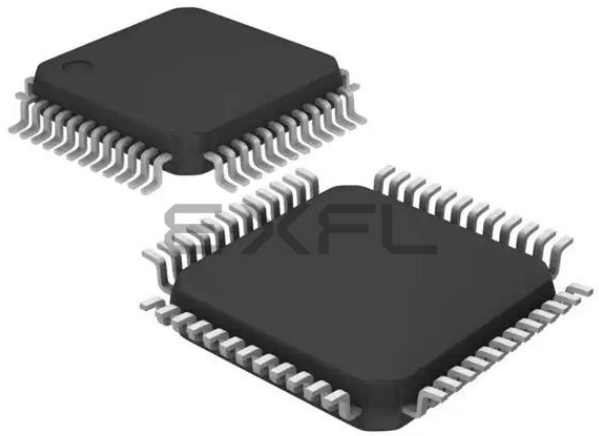

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	51.34MHz
Connectivity	I²C, LINbus, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	40
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 13x12b; D/A 3x5b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s08mp16vlfr

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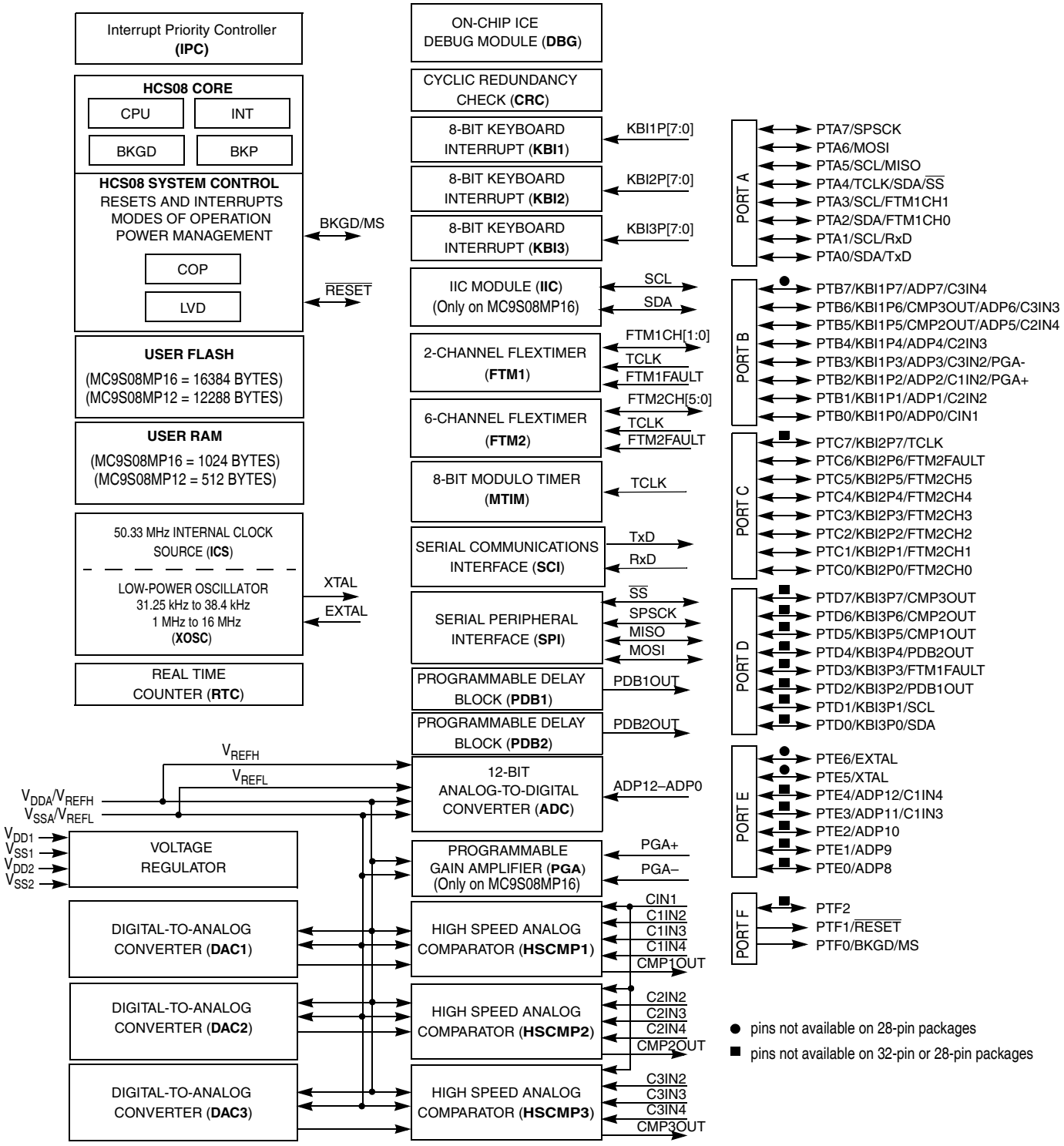
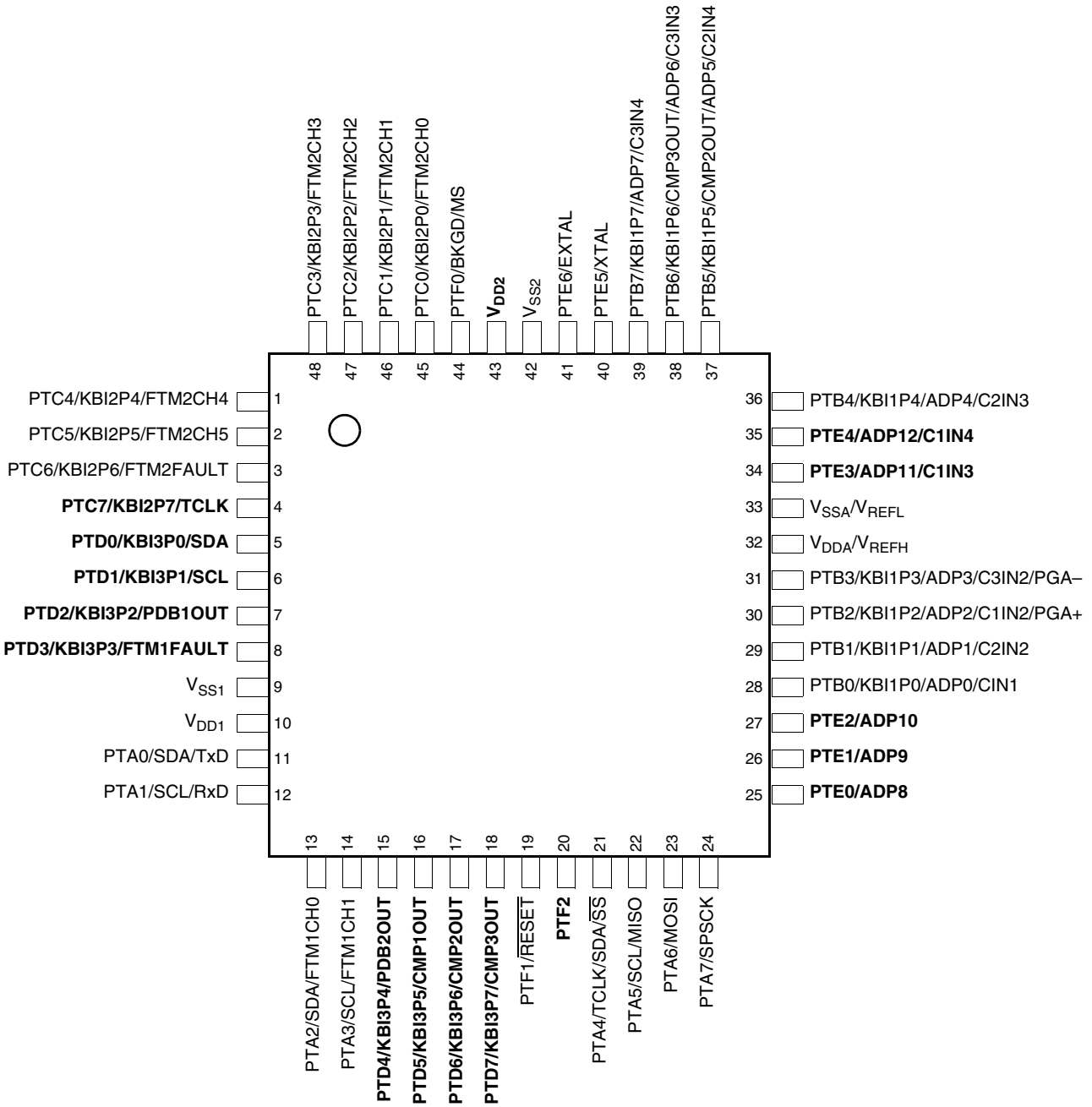


Notes: When PTF1 is configured as RESET, pin becomes bi-directional with output being open-drain drive containing an internal pull-up device.
When PTF0 is configured as BKGD, pin becomes bi-directional.
V_{DD2} pad is tied internally on 32-pin and 28-pin packages,
V_{SS2} pad is tied internally on 28-pin packages

Figure 1. MC9S08MP16 Series Block Diagram

1 Pin Assignments

This section shows the pin assignments for the MC9S08MP16 Series devices.



Note: Pins in **bold** are lost in the next lower pin count package.

Figure 2. MC9S08MP16 Series in 48-LQFP

Table 1. Pin Availability by Package Pin-Count

Pin Number			<-- Lowest Priority --> Highest				
48	32 LQFP	28	Port Pin	Alt 1	Alt 2	Alt3	Alt4
1	3	5	PTC4	KBI2P4	FTM2CH4		
2	4	6	PTC5	KBI2P5	FTM2CH5		
3	5	7	PTC6	KBI2P6	FTM2FAULT		
4	—	—	PTC7	KBI2P7	TCLK[1]		
5	—	—	PTD0	KBI3P0	SDA[5]		
6	—	—	PTD1	KBI3P1	SCL[5]		
7	—	—	PTD2	KBI3P2	PDB1OUT		
8	—	—	PTD3	KBI3P3	FTM1FAULT		
9	6	8					V_{SS1}
10	7	9					V_{DD1}
11	8	10	PTA0	SDA[5]	TxD		
12	9	11	PTA1	SCL[5]	RxD		
13	10	12	PTA2	SDA[5]	FTM1CH0		
14	11	13	PTA3	SCL[5]	FTM1CH1		
15	—	—	PTD4	KBI3P4	PDB2OUT		
16	—	—	PTD5	KBI3P5	CMP1OUT		
17	—	—	PTD6	KBI3P6	CMP2OUT[2]		
18	—	—	PTD7	KBI3P7	CMP3OUT[3]		
19	12	14	PTF1	$\overline{\text{RESET}}$[4]			
20	—	—	PTF2				
21	13	15	PTA4	TCLK[1]	SDA[5]	$\overline{SS}$	
22	14	16	PTA5		SCL[5]	MISO	
23	15	17	PTA6			MOSI	
24	16	18	PTA7			SPSCK	
25	—	—	PTE0		ADP8		
26	—	—	PTE1		ADP9		
27	—	—	PTE2		ADP10		
28	17	19	PTB0	KBI1P0	ADP0[6]	CIN1[6]	
29	18	20	PTB1	KBI1P1	ADP1[6]	C2IN2[6]	
30	19	21	PTB2	KBI1P2	ADP2[6]	C1IN2[6]	PGA+[6]
31	20	22	PTB3	KBI1P3	ADP3[6]	C3IN2[6]	PGA–[6]
32	21	23					V_{DDA}/V_{REFH}
33	22	24					V_{SSA}/V_{REFL}
34	—	—	PTE3		ADP11[6]	C1IN3[6]	

Table 1. Pin Availability by Package Pin-Count (continued)

Pin Number			<-- Lowest **Priority** --> Highest				
48	**32 LQFP**	**28**	**Port Pin**	**Alt 1**	**Alt 2**	**Alt3**	**Alt4**
35	—	—	PTE4		ADP12[6]	C1IN4[6]	
36	23	25	PTB4	KBI1P4		ADP4[6]	C2IN3[6]
37	24	26	PTB5	KBI1P5	CMP2OUT[2]	ADP5[6]	C2IN4[6]
38	25	27	PTB6	KBI1P6	CMP3OUT[3]	ADP6[6]	C3IN3[6]
39	26	—	PTB7	KBI1P7		ADP7[6]	C3IN4[6]
40	27	—	PTE5	XTAL			
41	28	—	PTE6	EXTAL			
42	29	—					V_{SS2}
43	—	—					V_{DD2}
44	30	28	PTF0	BKGD	MS		
45	31	1	PTC0	KBI2P0	FTM2CH0		
46	32	2	PTC1	KBI2P1	FTM2CH1		
47	1	3	PTC2	KBI2P2	FTM2CH2		
48	2	4	PTC3	KBI2P3	FTM2CH3		

1 TCLK pin can be repositioned using TCLKPS in SOPT2. Default reset location is PTC7.

2 HSCMP2 output CMP2OUT can be repositioned using the CMP2OPS in the SOPT2 register. Default reset location is PTD6.

3 HSCMP3 output CMP3OUT can be repositioned using the CMP3OPS in the SOPT2 register. Default reset location is PTD7.

4 Pin is open drain with an internal pullup that is always enabled. Pin does not contain a clamp diode to V_{DD} and should not be driven above V_{DD}. The voltage measured on the internally pulled up $\overline{\text{RESET}}$ will not be pulled to V_{DD}. The internal gates connected to this pin are pulled to V_{DD}.

5 IIC pins SDA and SCL can be repositioned using IICPS in SOPT2. Default reset locations are PTD0 and PTD1.

6 If ADC, HSCMP, or PGA is enabling a shared analog input pin, each has access to the pin.

2 Electrical Characteristics

2.1 Introduction

This section contains electrical and timing specifications for the MC9S08MP16 Series of microcontrollers available at the time of publication.

Table 7. DC Characteristics (continued)

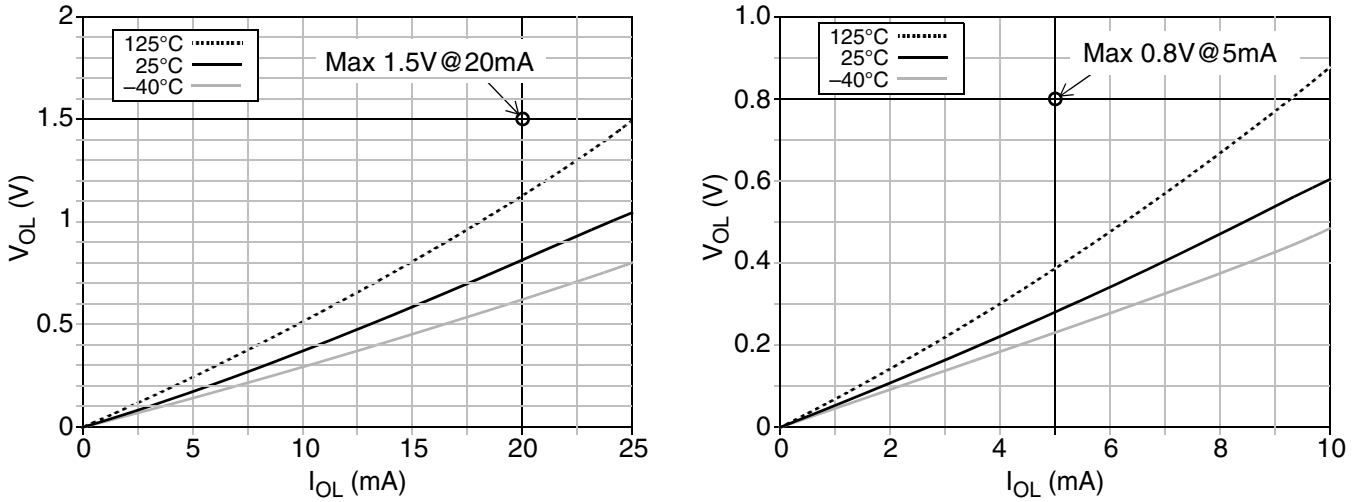
Num	C	Characteristic	Symbol	Condition	Min	Typ[1]	Max	Unit
4	C	All I/O pins (except PTF1/$\overline{\text{RESET}}$)	V_{OH}	5 V, I_{Load} = –4 mA	V_{DD} – 1.5	—	—	V
	P	low-drive strength		5 V, I_{Load} = –2 mA	V_{DD} – 0.8	—	—	
	C	Output high		3 V, I_{Load} = –1 mA	V_{DD} – 0.8	—	—	
	C	voltage		5 V, I_{Load} = –20 mA	V_{DD} – 1.5	—	—	
	P	high-drive strength		5 V, I_{Load} = –10 mA	V_{DD} – 0.8	—	—	
	C			3 V, I_{Load} = –5 mA	V_{DD} – 0.8	—	—	
5	D	Output high current — Max total I_{OH} for all ports	I_{OHT}	$V_{OUT} < V_{DD}$	0	—	–100	mA
6	C	All I/O pins	V_{OL}	5 V, I_{Load} = 4 mA	—	—	1.5	V
	P	(except PTF1/$\overline{\text{RESET}}$)		5 V, I_{Load} = 2 mA	—	—	0.8	
	C	low-drive strength		3 V, I_{Load} = 1 mA	—	—	0.8	
	C	All I/O pins		5 V, I_{Load} = 20 mA	—	—	1.5	
	P	Output low (Except PTF1/$\overline{\text{RESET}}$)		5 V, I_{Load} = 10 mA	—	—	0.8	
	C	voltage high-drive strength		3 V, I_{Load} = 5 mA	—	—	0.8	
7	C	PTF1/$\overline{\text{RESET}}$		5 V, I_{Load} = 3.2 mA	—	—	1.5	
8	P			5 V, I_{Load} = 1.6 mA	—	—	0.8	
9	C			3 V, I_{Load} = 0.8 mA	—	—	0.8	
10	D	Output low current — Max total I_{OL} for all ports	I_{OLT}	$V_{OUT} > V_{SS}$	0	—	100	mA
11	P	Input high voltage; all digital inputs	V_{IH}	5V	0.65 x V_{DD}	—	—	V
	C			3V	0.7 x V_{DD}	—	—	
12	P	Input low voltage; all digital inputs	V_{IL}	5V	—	—	0.35 x V_{DD}	V
	C			3V	—	—	0.35 x V_{DD}	
13	C	Input hysteresis	V_{hys}		0.06 x V_{DD}			V
14	P	Input leakage current (per pin)	$\lvert I_{In} \rvert$	$V_{In} = V_{DD}$ or V_{SS}	—	—	1	µA
15	P	Hi-Z (off-state) leakage current (per pin)						
		input/output port pins	$\lvert I_{OZ} \rvert$	$V_{In} = V_{DD}$ or V_{SS}	—	—	1	µA
		PTF1/$\overline{\text{RESET}}$, PTE5/XTAL pins		$V_{In} = V_{DD}$ or V_{SS}	—	—	2	µA
16	P	Pullup or Pulldown[3] resistors; when enabled — I/O pins	R_{PU},R_{PD}		17	37	52	kΩ
	C	PTF1/$\overline{\text{RESET}}$[4]	R_{PU}		17	37	52	kΩ
17	D	DC injection current [5, 6, 7, 8] — Single pin limit	I_{IC}	$V_{IN} > V_{DD}$	0	—	2	mA
				$V_{IN} < V_{SS}$	0	—	–0.2	mA
		Total MCU limit, includes sum of all stressed pins		$V_{IN} > V_{DD}$	0	—	25	mA
				$V_{IN} < V_{SS}$	0	—	–5	mA

7 All functional non-supply pins except PTF1/$\overline{\text{RESET}}$ are internally clamped to V_{SS} and V_{DD}.

8 The PTF1/$\overline{\text{RESET}}$ pin does not have a clamp diode to V_{DD}. Do not drive this pin above V_{DD}.

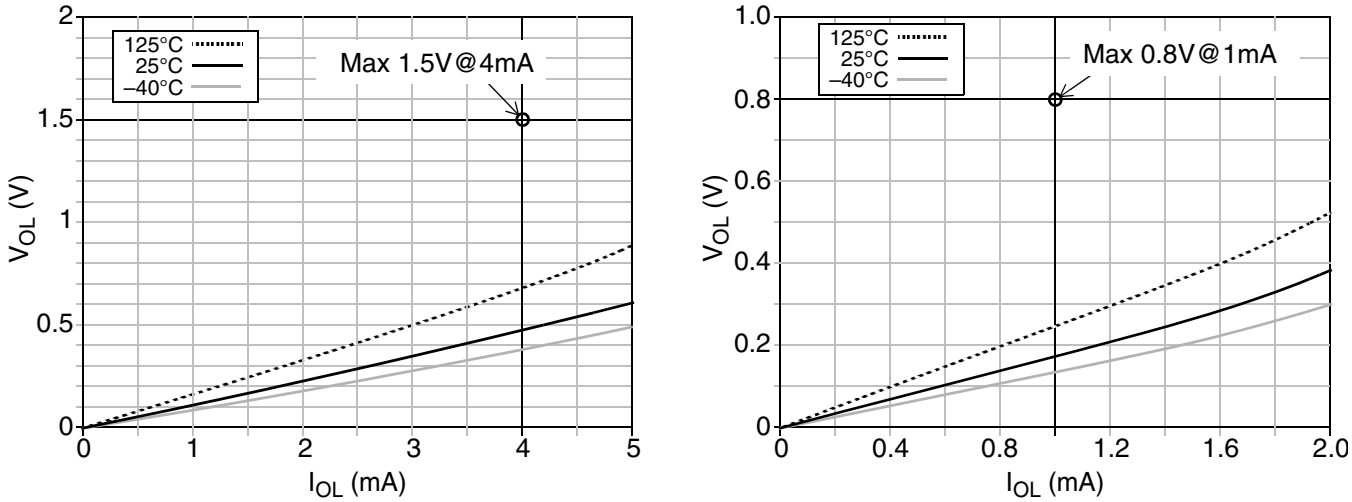
9 Maximum is highest voltage that POR is guaranteed.

10 Factory trimmed at V_{DD} = 5.0 V



a) V_{DD} = 5V, High Drive **b) V_{DD} = 3V, High Drive**

Figure 5. Typical V_{OL} vs I_{OL}, High Drive Strength (except PTF1/RESET)



a) V_{DD} = 5V, Low Drive **b) V_{DD} = 3V, Low Drive**

Figure 6. Typical V_{OL} vs I_{OL}, Low Drive Strength (except PTF1/RESET)

Table 8. Supply Current Characteristics (continued)

Num	C	Parameter	Symbol	V_{DD} (V)	Typ[1]	Max[2]	Unit
10	C	LVD adder to stop3 (LVDE = LVDSE = 1)	$S3I_{DDLVD}$	5	110	180	µA
				3	90	160	µA
11	C	Adder to stop3 for oscillator enabled[8] (EREFSTEN =1)	$S3I_{DDOSC}$	5,3	5	8	µA

1 Typical values are based on characterization data at 25°C. See Figure 9 through Figure 14 for typical curves across temperature and voltage.

2 Max values in this column apply for the full operating temperature range of the device unless otherwise noted.

3 All modules except ADC active, ICS configured for FBELP, and does not include any dc loads on port pins

4 All modules except ADC active, ICS configured for FEI, and does not include any dc loads on port pins

5 All modules except ADC active, ICS configured for FEI, and does not include any dc loads on port pins

6 Stop currents are tested in production for 25°C on all parts. Tests at other temperatures depend upon the part number suffix and maturity of the product. Freescale may eliminate a test insertion at a particular temperature from the production test flow once sufficient data has been collected and is approved.

7 Most customers are expected to find that auto-wakeup from stop2 or stop3 can be used instead of the higher current wait mode.

8 Values given under the following conditions: low range operation (RANGE = 0) with a 32.768kHz crystal and low power mode (HGO = 0).

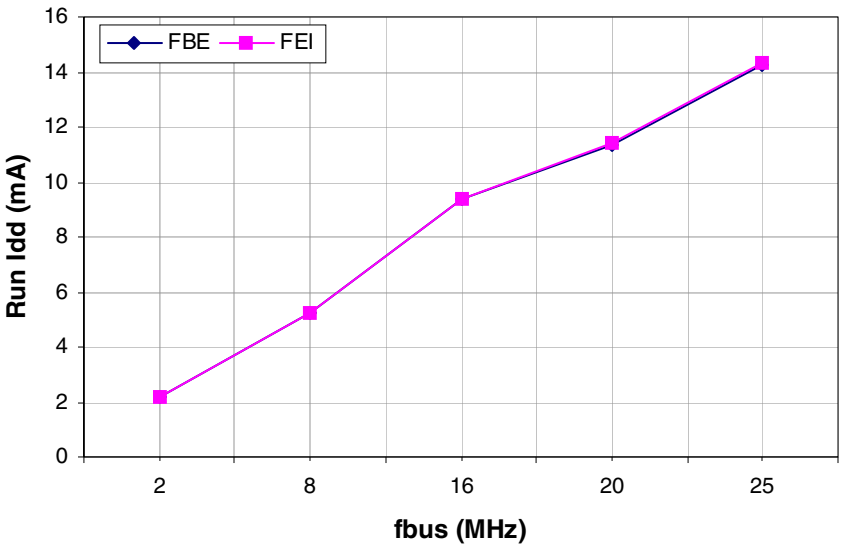


Figure 9. Typical Run I_{DD} vs. Bus Frequency (V_{DD} = 5V)

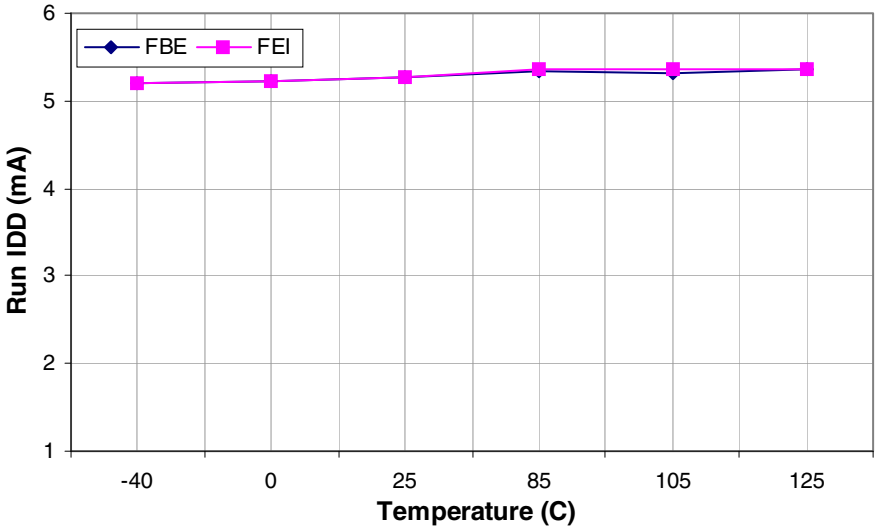


Figure 10. Typical Run I_{DD} vs. Temperature (V_{DD} = 5V, f_{bus} = 8MHz)

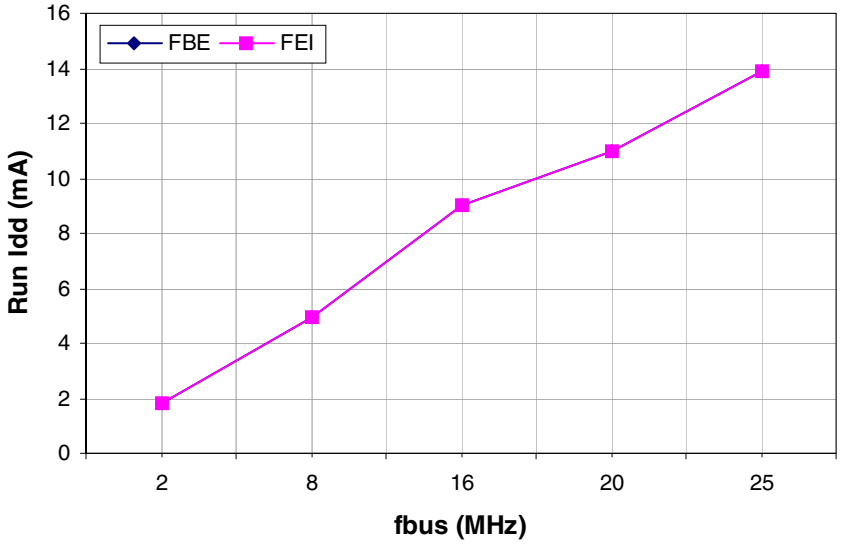


Figure 11. Typical Run I_{DD} vs. Bus Frequency (V_{DD} = 3V)

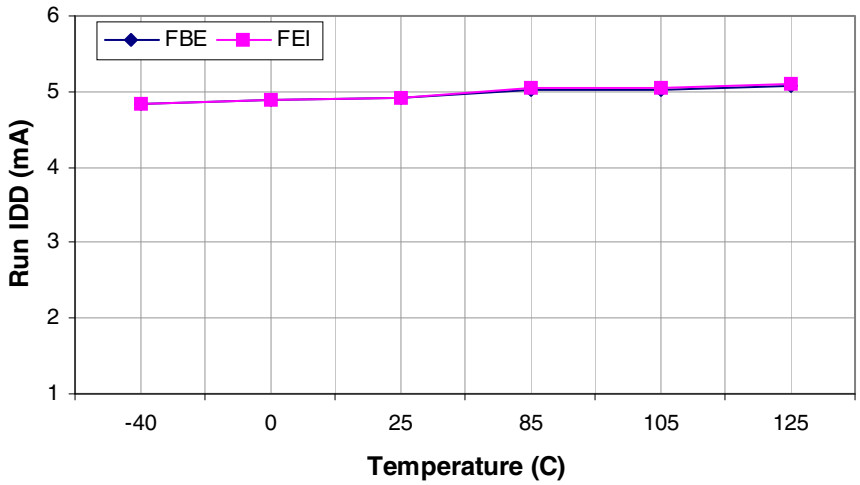


Figure 12. Typical Run I_{DD} vs. Temperature (V_{DD} = 3V, f_{bus} = 8MHz)

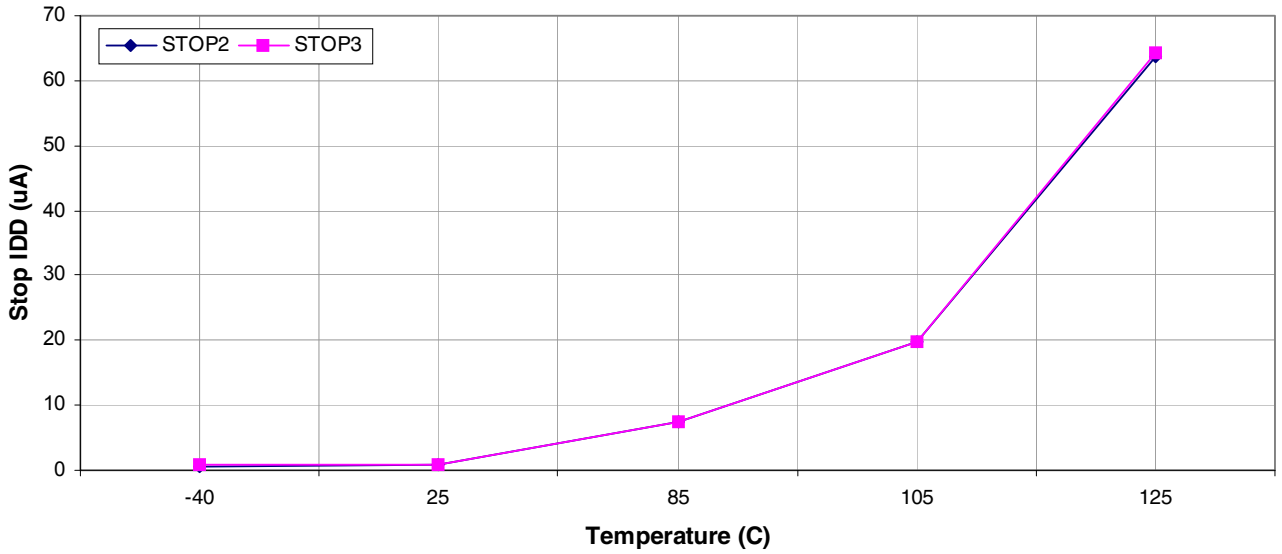


Figure 13. Typical Stop I_{DD} vs. Temperature (V_{DD} = 5V)

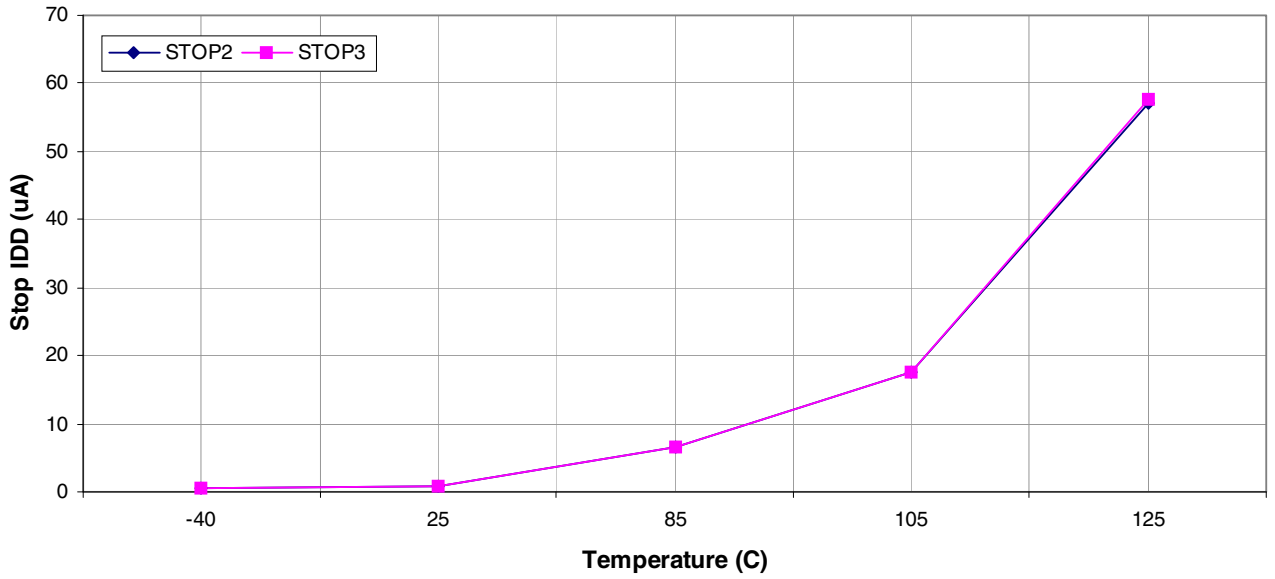


Figure 14. Typical Stop I_{DD} vs. Temperature (V_{DD} = 3V)

2.8 External Oscillator (XOSC) Characteristics

Table 9. Oscillator Electrical Specifications

Num	C	Rating	Symbol	Min	Typ[1]	Max	Unit
1	C	Oscillator crystal or resonator (EREFS = 1, ERCLKEN = 1)					
		Low range (RANGE = 0)	f_{lo}	32	—	38.4	kHz
		High range (RANGE = 1) FEE[2] or FBE[3] mode	f_{hi}	1	—	16	MHz
		High range (RANGE = 1, HGO = 1) FBELP mode	f_{hi-hgo}	1	—	16	MHz
		High range (RANGE = 1, HGO = 0) FBELP mode	f_{hi-lp}	1	—	8	MHz
2	—	Load capacitors	C_1, C_2	See crystal or resonator manufacturer's recommendation.			
3	—	Feedback resistor					
		Low range (32 kHz to 100 kHz)	R_F	—	10	—	MΩ
		High range (1 MHz to 16 MHz)		—	1	—	
4	—	Series resistor					
		Low range, low gain (RANGE = 0, HGO = 0)	R_S	—	0	—	kΩ
		Low range, high gain (RANGE = 0, HGO = 1)		—	100	—	
		High range, low gain (RANGE = 1, HGO = 0)		—	0	—	
		High range, high gain (RANGE = 1, HGO = 1)					
		≥ 8 MHz		—	0	0	
		4 MHz		—	0	10	
		1 MHz		—	0	20	

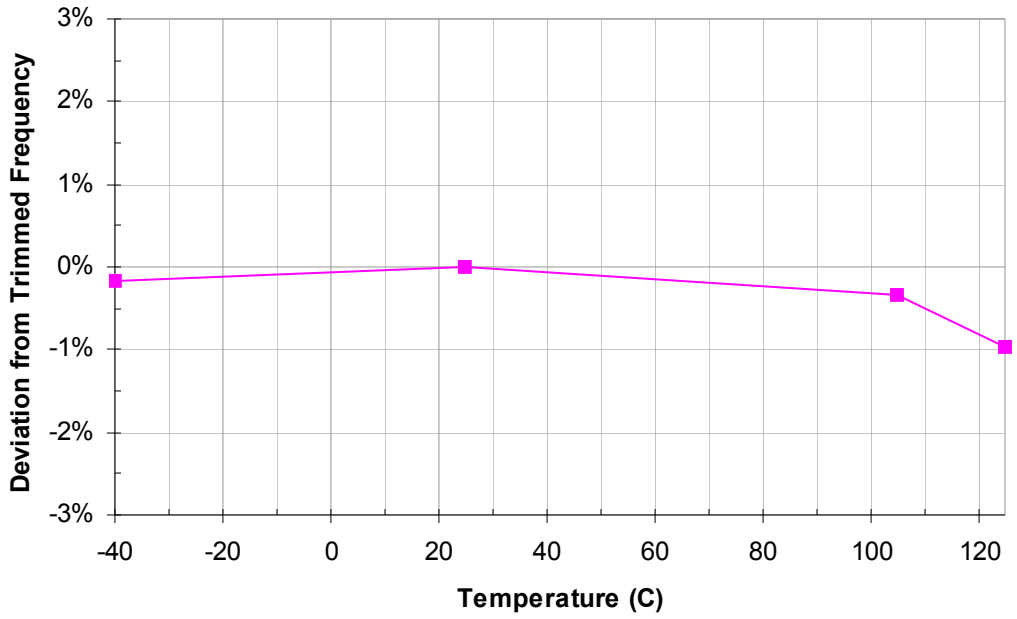


Figure 15. Typical Frequency Deviation vs Temperature (ICS Trimmed to 25 MHz bus@25°C, 5V, FEI)[1]

2.10 ADC Characteristics

Table 11. 12-bit ADC Operating Conditions

Characteristic	Conditions	Symbol	Min	Typ[1]	Max	Unit	Comment
Supply voltage	Absolute	V_{DDA}	2.7	—	5.5	V	
Input Voltage		V_{ADIN}	V_{REFL}	—	V_{REFH}	V	
Input Capacitance		C_{ADIN}	—	4.5	5.5	pF	
Input Resistance		R_{ADIN}	—	3	5	kΩ	
Analog Source Resistance	12 bit mode f_{ADCK} > 4MHz f_{ADCK} < 4MHz	R_{AS}	 — —	 — —	 2 5	kΩ	External to MCU
	10 bit mode f_{ADCK} > 4MHz f_{ADCK} < 4MHz		 — —	 — —	 5 10		
	8 bit mode (all valid f_{ADCK})		—	—	10		
ADC Conversion Clock Freq.	High Speed (ADLPC=0)	f_{ADCK}	0.4	—	8.0	MHz	
	Low Power (ADLPC=1)		0.4	—	4.0		

[1] Typical values assume V_{DDAD} = 5.0V, Temp = 25°C, f_{ADCK}=1.0MHz unless otherwise stated. Typical values are for reference only and are not tested in production.

1. Based on the average of several hundred units from a typical characterization lot.

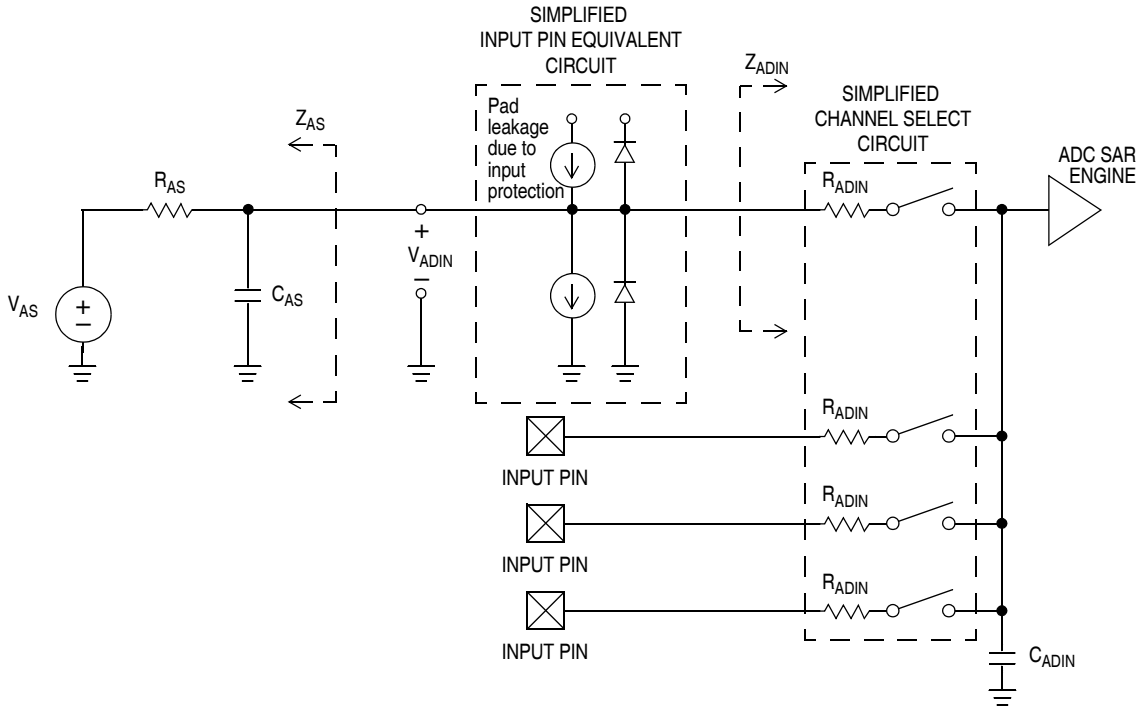


Figure 16. ADC Input Impedance Equivalency Diagram

Table 12. 12-bit ADC Characteristics (V_{REFH} = V_{DDAD}, V_{REFL} = V_{SSAD})

C	Characteristic	Conditions	Symb	Min	Typ[1]	Max	Unit	Comment
T	Supply Current ADLPC=1 ADLSMP=1 ADCO=1		I_{DDA}	—	133	—	μA	
T	Supply Current ADLPC=1 ADLSMP=0 ADCO=1		I_{DDA}	—	218	—	μA	
T	Supply Current ADLPC=0 ADLSMP=1 ADCO=1		I_{DDA}	—	327	—	μA	
T	Supply Current ADLPC=0 ADLSMP=0 ADCO=1		I_{DDA}	—	0.582	—	mA	
P	ADC Asynchronous Clock Source	High Speed (ADLPC=0)	f_{ADACK}	2	3.3	5	MHz	t_{ADACK} = $1/f_{ADACK}$
		Low Power (ADLPC=1)		1.25	2	3.3		

Table 12. 12-bit ADC Characteristics (V_{REFH} = V_{DDAD}, V_{REFL} = V_{SSAD}) (continued)

C	Characteristic	Conditions	Symb	Min	Typ[1]	Max	Unit	Comment
D	Conversion Time (Including sample time)	Short Sample (ADLSMP=0)	t_{ADC}	—	20	—	ADCK cycles	See ADC chapter in the Reference Manual for conversion time variances
		Long Sample (ADLSMP=1)		—	40	—		
D	Sample Time	Short Sample (ADLSMP=0)	t_{ADS}	—	3.5	—	ADCK cycles	
		Long Sample (ADLSMP=1)		—	23.5	—		
T	Temp Sensor Slope	-40°C to 25°C	m	—	3.266	—	mV/°C	
		25°C to 125°C		—	3.638	—		
T	Temp Sensor Voltage	25°C	V_{TEMP25}	—	1.396	—	mV	
T	Total Unadjusted Error	12 bit mode	E_{TUE}	—	±3.0	±6.5	LSB[2]	Includes quantization
P		10 bit mode		—	±1	±2.5		
T		8 bit mode		—	±0.5	±1.0		
T	Differential Non-Linearity	12 bit mode	DNL	—	±1.75	±3.5	LSB[2]	
P		10 bit mode[3]		—	±0.5	±1.0		
T		8 bit mode[3]		—	±0.3	±0.5		
T	Integral Non-Linearity	12 bit mode	INL	—	±1.5	±4.5	LSB[2]	
P		10 bit mode		—	±0.5	±1.0		
T		8 bit mode		—	±0.3	±0.5		
T	Zero-Scale Error	12 bit mode	E_{ZS}	—	±1.5	0.0/ -3.0	LSB[2]	V_{ADIN} = V_{SSAD}
P		10 bit mode		—	±0.5	±1.5		
T		8 bit mode		—	±0.5	±0.5		
T	Full-Scale Error	12 bit mode	E_{FS}	—	±1.0	+1.75/ −1.25	LSB[2]	V_{ADIN} = V_{DDAD}
T		10 bit mode		—	±0.5	±1		
T		8 bit mode		—	±0.5	±0.5		
D	Quantization Error	12 bit mode	E_Q	—	-1 to 0	—	LSB[2]	
		10 bit mode		—	—	±0.5		
		8 bit mode		—	—	±0.5		
D	Input Leakage Error	12 bit mode	E_{IL}	—	±1	—	LSB[2]	Pad leakage[4] * R_{AS}
		10 bit mode		—	±0.2	±2.5		
		8 bit mode		—	±0.1	±1		

1 Typical values assume V_{DDAD} = 5.0V, Temp = 25°C, f_{ADCK}=1.0MHz unless otherwise stated. Typical values are for reference only and are not tested in production.

2 1 LSB = $(V_{REFH} - V_{REFL})/2^N$

3 Monotonicity and No-Missing-Codes guaranteed in 10 bit and 8 bit modes

4 Based on input pad leakage current. Refer to pad electricals.

Table 15. Programmable Gain Amplifier Electrical Specifications (continued)

Num	C	Parameter	Symbol	Min	Typical	Max	Unit
4	D	Differential input voltage	$V_{DIFFMAX}$	$-\left(\frac{V_{DDA}-1.4}{2\times Gain}\right)$	0	$\frac{V_{DDA}-1.4}{2\times Gain}$	V
5	T	Linearity (@ voltage gain)[1] • 1x • 2x • 4x • 8x • 16x • 32x	L_V	 1 – 1/2 LSB 2 – 1/2 LSB 4 – 1 LSB 8 – 1 LSB 16 – 4 LSB 32 – 4 LSB	 1 2 4 8 16 32	 1 + 1/2 LSB 2 + 1/2 LSB 4 + 1 LSB 8 + 1 LSB 16 + 4 LSB 32 + 4 LSB	V/V
6	T	Max gain error	E_G	—	1	2	%
7a	D	PGA clock • normal mode (LP=0) • low power mode (LP=1)	f_{PGA}	 — —	 8[2] 4	 8[2] 4	MHz
7b	D	PGA sampling frequency[3]	f_{SAMPL}	—	$\frac{1}{\left(\frac{12+18\times NUM\_CLK\_GS}{f_{PGA}}\right)+\frac{43}{f_{ADC}}+\frac{5}{f_{BUS}}}$	—	Samples per second
8	D	Input signal bandwidth	BW	0	$f_{SAMPL} \div 8$	$f_{SAMPL} \div 2$	Hz
9	D	Charge pump clock frequency	f_{cpclk}	100	$f_{PGA} \div 4$	—	Hz

1 LSB in 12-bit resolution

2 8 MHz is required for PGA achieving 1 µs sampling time.

3 ADC in 12-bit mode, long sampling time, $f_{ADC} = f_{PGA}$

2.14 AC Characteristics

This section describes timing characteristics for each peripheral system.

2.14.1 Control Timing

Table 16. Control Timing

Num	C	Rating		Symbol	Min	Typ[1]	Max	Unit
1	D	Bus frequency ($t_{cyc} = 1/f_{Bus}$)	–40 to 105 °C	f_{Bus}	DC	—	25.67	MHz
			–40 to 125 °C	f_{Bus}	DC	—	20	MHz
2	P	Internal low power oscillator period		t_{LPO}	700	—	1300	µs
3	D	External reset pulse width[2]		t_{extrst}	100	—	—	ns
4	D	Reset low drive		t_{rstdrv}	34 x t_{cyc}	—	—	ns
5	D	BKGD/MS setup time after issuing background debug force reset to enter user or BDM modes		t_{MSSU}	500	—	—	ns
6	D	BKGD/MS hold time after issuing background debug force reset to enter user or BDM modes [3]		t_{MSH}	100	—	—	µs

2.14.4 SPI

Table 19 and Figure 22 through Figure 25 describe the timing requirements for the SPI system.

Table 19. SPI Electrical Characteristics

Num[1]	C	Rating[2]	Symbol	Min	Max	Unit
1	D	Cycle time Master Slave	 t_{SCK} t_{SCK}	 2 4	 4096 —	 t_{cyc} t_{cyc}
2	D	Enable lead time Master Slave	 t_{Lead} t_{Lead}	 — 1/2	 1/2 —	 t_{SCK} t_{SCK}
3	D	Enable lag time Master Slave	 t_{Lag} t_{Lag}	 — 1/2	 1/2 —	 t_{SCK} t_{SCK}
4	D	Clock (SPSCK) high time Master and Slave	t_{SCKH}	1/2 t_{SCK} – 25	—	ns
5	D	Clock (SPSCK) low time Master and Slave	t_{SCKL}	1/2 t_{SCK} – 25	—	ns
6	D	Data setup time (inputs) Master Slave	 $t_{SI(M)}$ $t_{SI(S)}$	 30 30	 — —	 ns ns
7	D	Data hold time (inputs) Master Slave	 $t_{HI(M)}$ $t_{HI(S)}$	 30 30	 — —	 ns ns
8	D	Access time, slave[3]	t_A	0	40	ns
9	D	Disable time, slave[4]	t_{dis}	—	40	ns
10	D	Data setup time (outputs) Master Slave	 t_{SO} t_{SO}	 — —	 25 25	 ns ns
11	D	Data hold time (outputs) Master Slave	 t_{HO} t_{HO}	 –10 –10	 — —	 ns ns
12	D	Operating frequency Master (SPIFE=0) Slave (SPIFE=0) Master (SPIFE=1) Slave (SPIFE=1)	f_{op}	f_{Bus}/4096 dc f_{Bus}/4096 dc	8[5] f_{Bus}/4 5[6] 5[6]	MHz MHz MHz

1 Refer to Figure 22 through Figure 25.

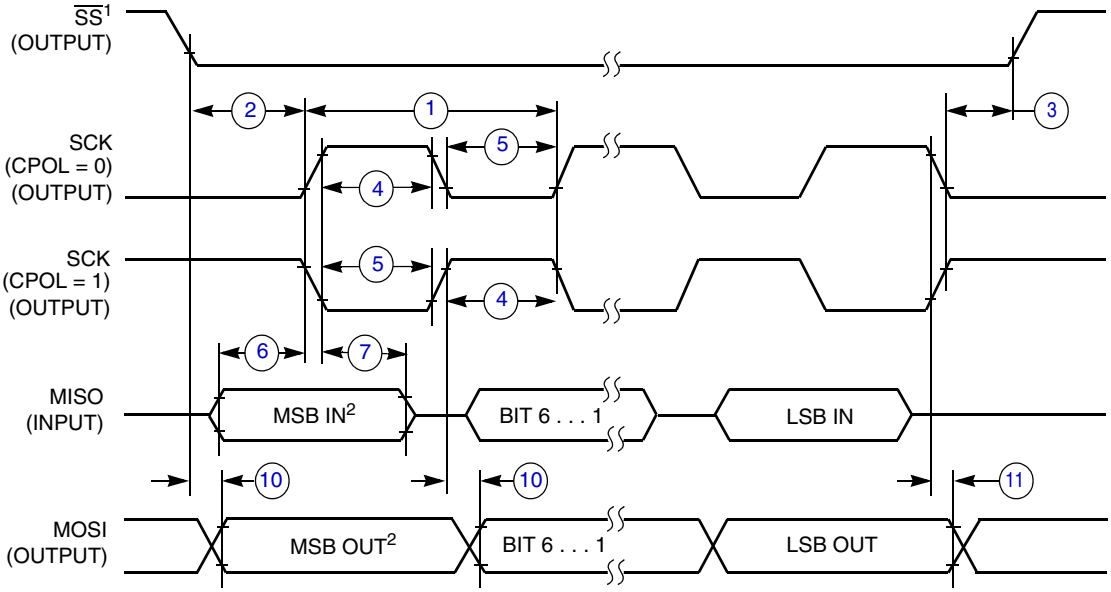
2 All timing is shown with respect to 20% V_{DD} and 70% V_{DD}, unless noted; 100 pF load on all SPI pins. All timing assumes slew rate control disabled and high drive strength enabled for SPI output pins.

3 Time to data active from high-impedance state.

4 Hold time to high-impedance state.

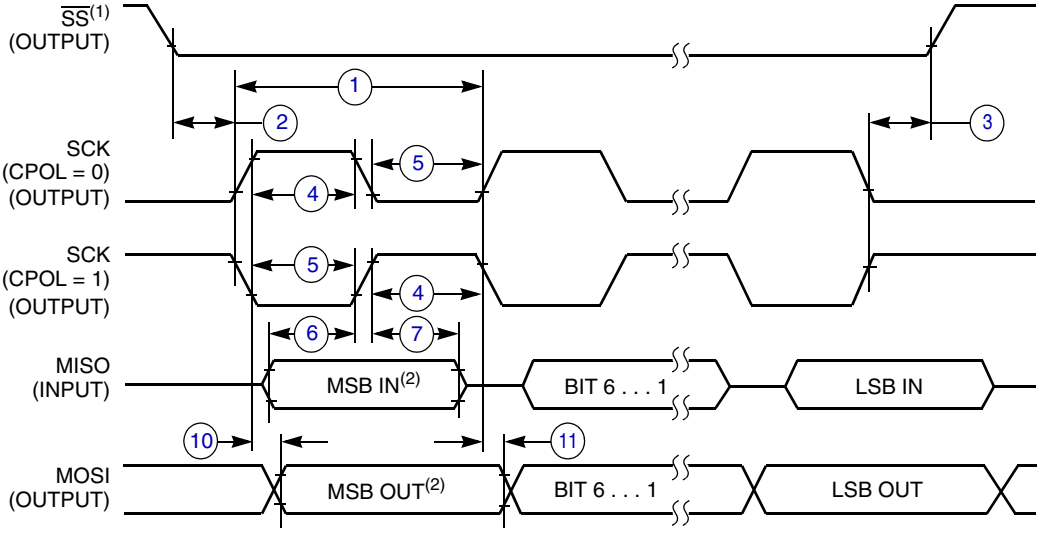
5 Maximum baud rate must be limited to 8 MHz.

6 Maximum baud rate must be limited to 5 MHz due to input filter characteristics.



NOTES:
1. $\overline{SS}$ output mode (MODFEN = 1, SSOE = 1).
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 22. SPI Master Timing (CPHA = 0)



NOTES:
1. $\overline{SS}$ output mode (MODFEN = 1, SSOE = 1).
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 23. SPI Master Timing (CPHA = 1)

2.15 Flash Memory Specifications

This section provides details about program/erase times and program-erase endurance for the flash memory.

Program and erase operations do not require any special power sources other than the normal V_{DD} supply. For more detailed information about program/erase operations, see the Memory section.

Table 20. Flash Memory Characteristics

Num	C	Characteristic	Symbol	Min	Typical	Max	Unit
1	—	Supply voltage for program/erase -40°C to 125°C	$V_{prog/erase}$	2.7		5.5	V
2	—	Supply voltage for read operation	V_{Read}	2.7		5.5	V
3	—	Internal FCLK frequency[1]	f_{FCLK}	150		200	kHz
4	—	Internal FCLK period (1/FCLK)	t_{Fcyc}	5		6.67	µs
5	C	Byte program time (random location)[2]	t_{prog}	9			t_{Fcyc}
6	—	Byte program time (burst mode)[2]	t_{Burst}	4			t_{Fcyc}
7	D	Page erase time[2]	t_{Page}	4000			t_{Fcyc}
8	D	Mass erase time[2]	t_{Mass}	20,000			t_{Fcyc}
9	C	Byte program current[3]	R_{IDDBP}	—	4	—	mA
10	C	Page erase current[3]	R_{IDDPE}	—	6	—	mA
11	C	Program/erase endurance[4] T_L to T_H = –40°C to + 125°C T = 25°C		10,000	— 100,000	— —	cycles
12	C	Data retention[5]	t_{D_ret}	15	100	—	years

1 The frequency of this clock is controlled by a software setting.

2 These values are hardware state machine controlled. User code does not need to count cycles. This information supplied for calculating approximate time to program and erase.

3 The program and erase currents are additional to the standard run I_{DD}. These values are measured at room temperatures with V_{DD} = 5.0 V, bus frequency = 4.0 MHz.

4 **Typical endurance for Flash** is based upon the intrinsic bit cell performance. For additional information on how Freescale defines typical endurance, please refer to Engineering Bulletin EB619/D, *Typical Endurance for Nonvolatile Memory.*

5 **Typical data retention** values are based on intrinsic capability of the technology measured at high temperature and de-rated to 25°C using the Arrhenius equation. For additional information on how Freescale defines typical data retention, please refer to Engineering Bulletin EB618/D, *Typical Data Retention for Nonvolatile Memory.*

2.16 EMC Performance

Electromagnetic compatibility (EMC) performance is highly dependant on the environment in which the MCU resides. Board design and layout, circuit topology choices, location and characteristics of external components as well as MCU software operation all play a significant role in EMC performance. The system designer should consult Freescale applications notes such as AN2321, AN1050, AN1263, AN2764, and AN1259 for advice and guidance specifically targeted at optimizing EMC performance.

2.16.1 Radiated Emissions

Microcontroller radiated RF emissions are measured from 150 kHz to 1 GHz using the TEM/GTEM Cell method in accordance with the IEC 61967-2 and SAE J1752/3 standards. The measurement is performed with the microcontroller installed on a

custom EMC evaluation board while running specialized EMC test software. The radiated emissions from the microcontroller are measured in a TEM cell in two package orientations (North and East).

The maximum radiated RF emissions of the tested configuration in all orientations are less than or equal to the reported emissions levels.

Table 21. Radiated Emissions, Electric Field

Parameter	Symbol	Conditions	Frequency	f_{OSC}/f_{BUS}	Level[1] (Max)	Unit
Radiated emissions, electric field	V_{RE_TEM}	V_{DD} = 5V TA = +25°C package type 48 LQFP	0.15 – 50 MHz	4 MHz crystal 2 MHz bus	3	dBμV
			50 – 150 MHz		8	
			150 – 500 MHz		–4	
			500 – 1000 MHz		–8	
			IEC Level[2]		N	—
			SAE Level[3]		1	—

1 Data based on qualification test results. The reported emission level is the value of the maximum emission, rounded up to the next whole number, from among the measured orientations in each frequency range.

2 IEC level maximums: N ≤ 12 dBμV, L ≤ 24 dBμV, I ≤ 36 dBμV

3 SAE level maximums: 1 ≤ 10 dBμV, 2 ≤ 20 dBμV, 3 ≤ 30 dBμV, 4 ≤ 40 dBμV

3 Ordering Information

This section contains ordering information for MC9S08MP16 and MC9S08MP12 devices.

Table 22. Device and Package Options

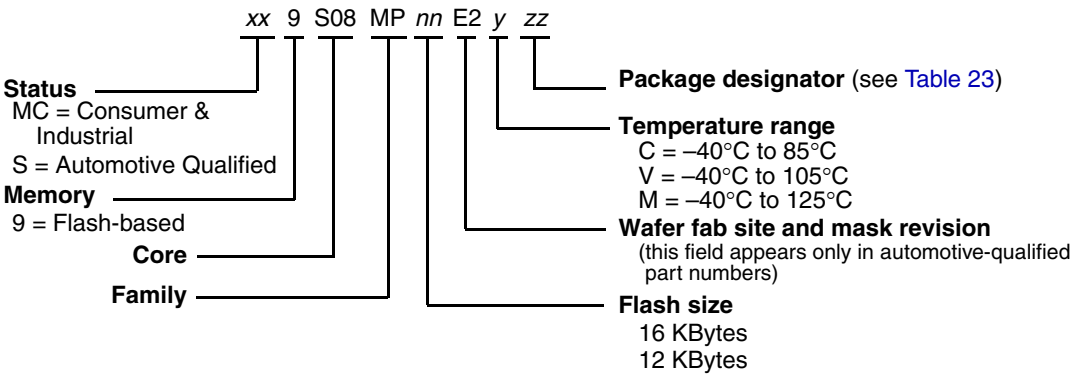
Device Number[1]	Temp Range	Memory		Available Packages[2]		
		Flash	RAM	48-Pin	32-Pin	28-Pin
Consumer and Industrial Qualification						
MC9S08MP16	V	16K	1024	48 LQFP	32 LQFP	28 SOIC
MC9S08MP12	V	12K	512	—	—	28 SOIC
Automotive Qualification						
S9S08MP16	C, V, M	16K	1024	48 LQFP	—	—

1 See the *MC9S08MP16RM Reference Manual* (MC9S08MP16RM) for a complete description of modules included on each device.

2 See Table 23 for package information.

3.1 Device Numbering Scheme

Example of the device numbering system:



4 Package Information

The latest package outline drawings are available on the product summary pages on our web site: http://www.freescale.com/8bit. The following table lists the document numbers per package. Use these numbers in the web page's keyword search engine to find the latest package outline drawings.

NOTE

The 32 LQFP and 28 SOIC are not qualified to meet automotive requirements.

Table 23. Package Descriptions

Pin Count	Package Type	Abbreviation	Designator	Case No.	Document No.
48	Low Quad Flat Pack	LQFP	LF	932-03	98ASH00962A
32	Low Quad Flat Pack	LQFP	LC	873A-03	98ASH70029A
28	Small Outline Integrated Circuit	SOIC	WL	751F-05	98ASB42345B

5 Related Documentation

Find the most current versions of all documents at http://www.freescale.com.

Reference Manual (MC9S08MP16RM)

Contains extensive product information including modes of operation, memory, resets and interrupts, register definition, port pins, CPU, and all module information.

6 Revision History

To provide the most up-to-date information, the revision of our documents on the World Wide Web are the most current. Your printed copy may be an earlier revision. To verify you have the latest information available, refer to:

http://www.freescale.com